

Notice of References Cited	Application/Control No. 10/619,707	Applicant(s)/Patent Under Reexamination PAEK ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,519,974	02-2003	Oh et al.	65/379
	B	US-5,931,984	08-1999	Drouart et al.	65/540
	C	US-5,637,130	06-1997	Nagayama et al.	65/435
	D	US-4,154,592	05-1979	Bailey, Alan C.	65/424
	E	US-2002/0095955	07-2002	Ball et al.	65/475
	F	US-2003/0041628	03-2003	Bird et al.	65/533
	G	US-2004/0089025	05-2004	Kuwahara et al.	065/382
	H	US-2002/0029591	03-2002	DICKINSON JR. et al.	65/379
	I	US-2001/0023598	09-2001	Kohmura et al.	65/377
	J	US-6,543,257	04-2003	Koaizawa et al.	65/489
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06056458 A	03-1994	Japan	FUJIMAKI et al.	C03B 37/029
	O	DE 4006839 A1	09-1991	Germany	LYSSON et al.	B01J 19/14
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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